

16th ANNUAL FIB SEM MEETING

MAY 22 – 23, 2024

Kossiakoff Center
Johns Hopkins Applied Physics Laboratory
Laurel, MD

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The FIB SEM 2024 Meeting will be returning to the Kossiakoff Center at the Johns Hopkins Applied Physics Laboratory. We will have two full days of presentations and tutorials by FIB users and vendors, highlighting interesting new FIB applications and the latest technology.

New this year will be student awards for best oral and poster presentation! Win up to \$500 to cover travel for the meeting (eligible expenses include hotel, food, airfare, rental vehicle/mileage). Please indicate in the registration form if you would like to be considered for an award.

Plenary Speaker: Jacques Gierak

Centre de Nanosciences et de Nanotechnologies

Ion source development with an eye towards exciting advances in new Ga and ionic liquid emitters designs

Currently accepting abstracts on:

- Semiconductor, materials, and biological FIB applications
- 2D & 3D FIB SEM analysis
- Specimen Preparation
- Novel FIB instrumentation and analytical capabilities
- Correlative workflows

Abstract Submission Deadline: April 12th, 2024

Abstracts should be 250 words or less in length. Please email your abstracts to fibsem2024@fibsem.net

There is no fee to attend the meeting, and breakfast and lunch will be provided! And as usual, there will be a Happy Hour event Wednesday evening at the K-Center.

Visit <https://fibsem.net> for more information.

Organizers

Nabil Bassim, Ken Livi, Keana Scott & Samantha Stambula



REGISTER TODAY

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16th-annual-fib-sem-meeting/](https://ccem.mcmaster.ca/events/16th-annual-fib-sem-meeting/)

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